

FIG. 1A

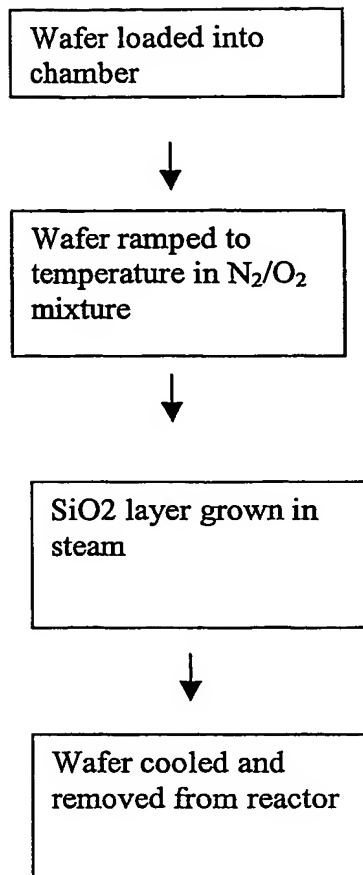
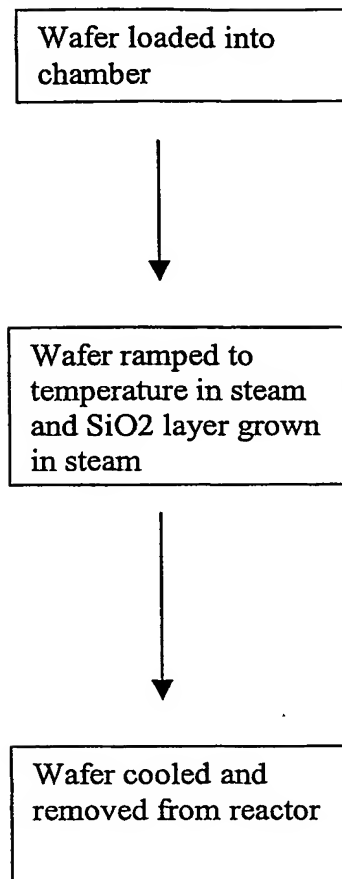
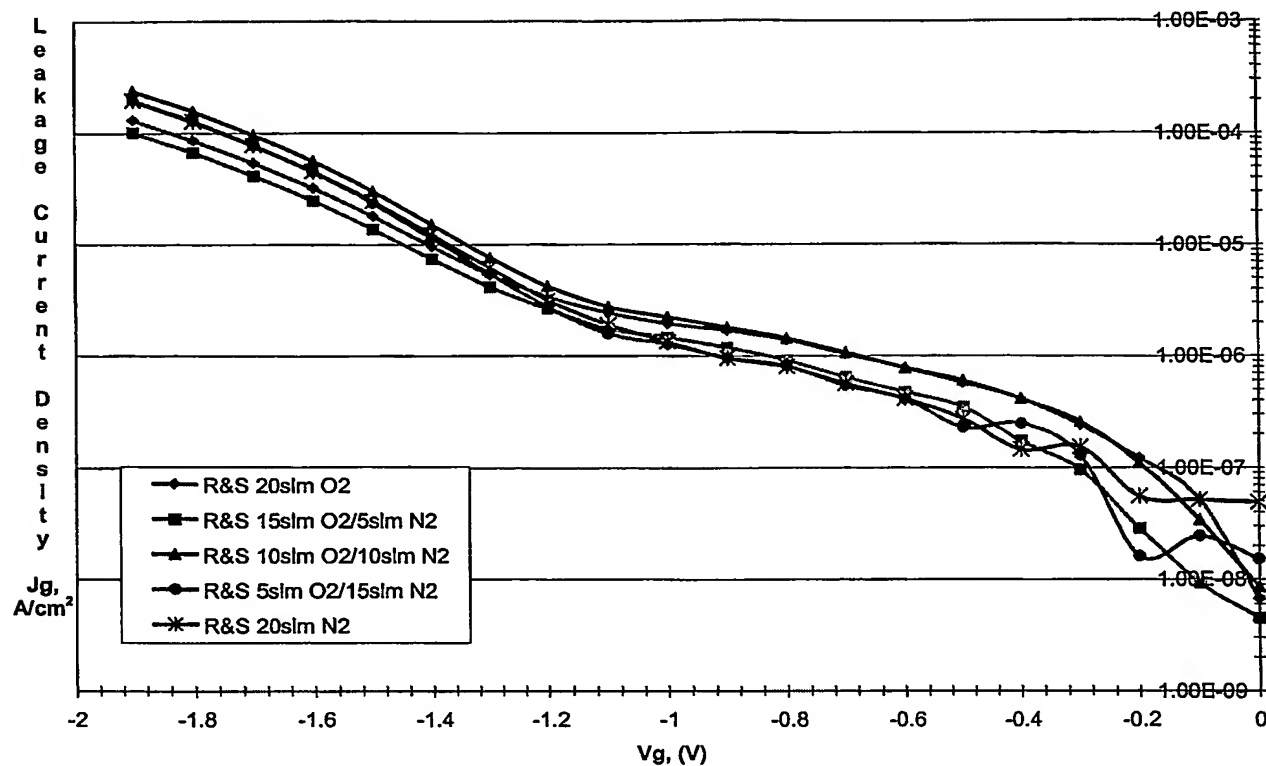
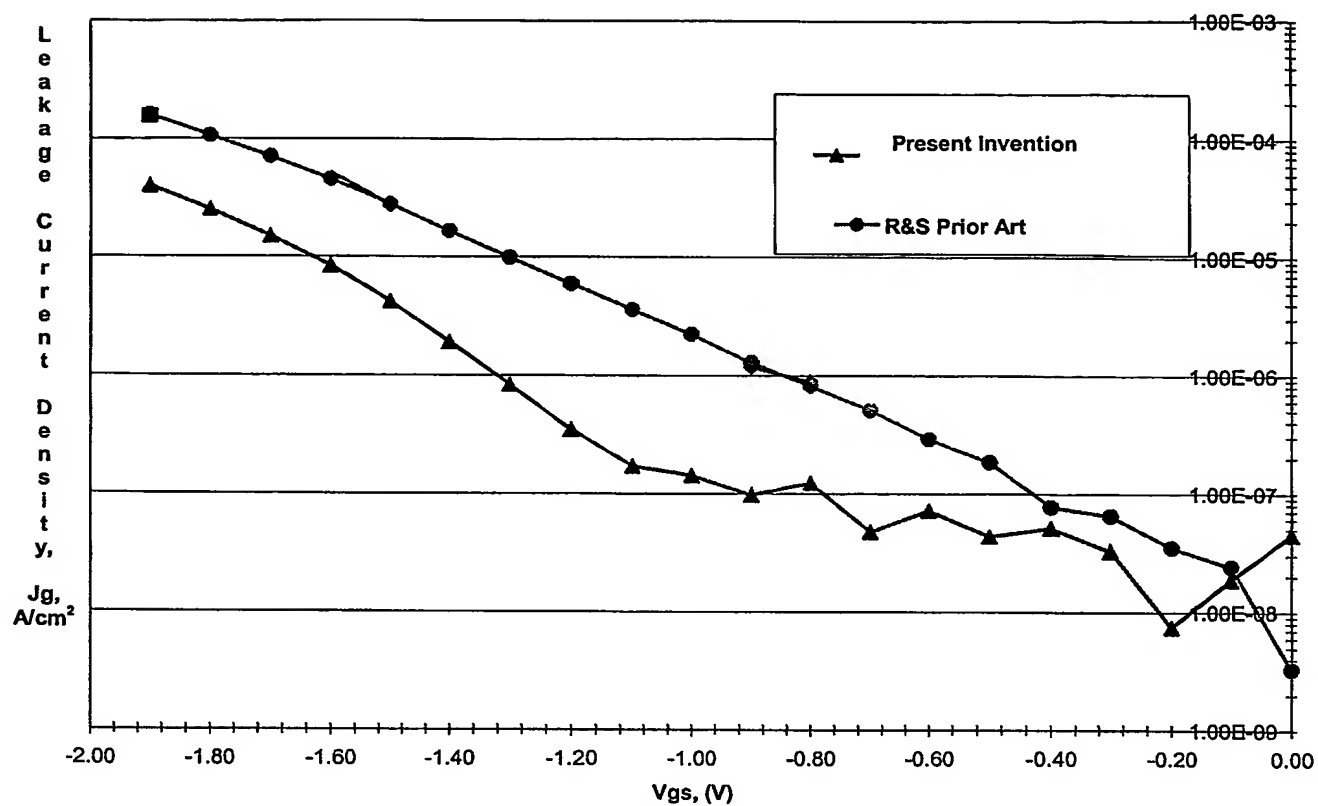
Prior Art

FIG. 1B

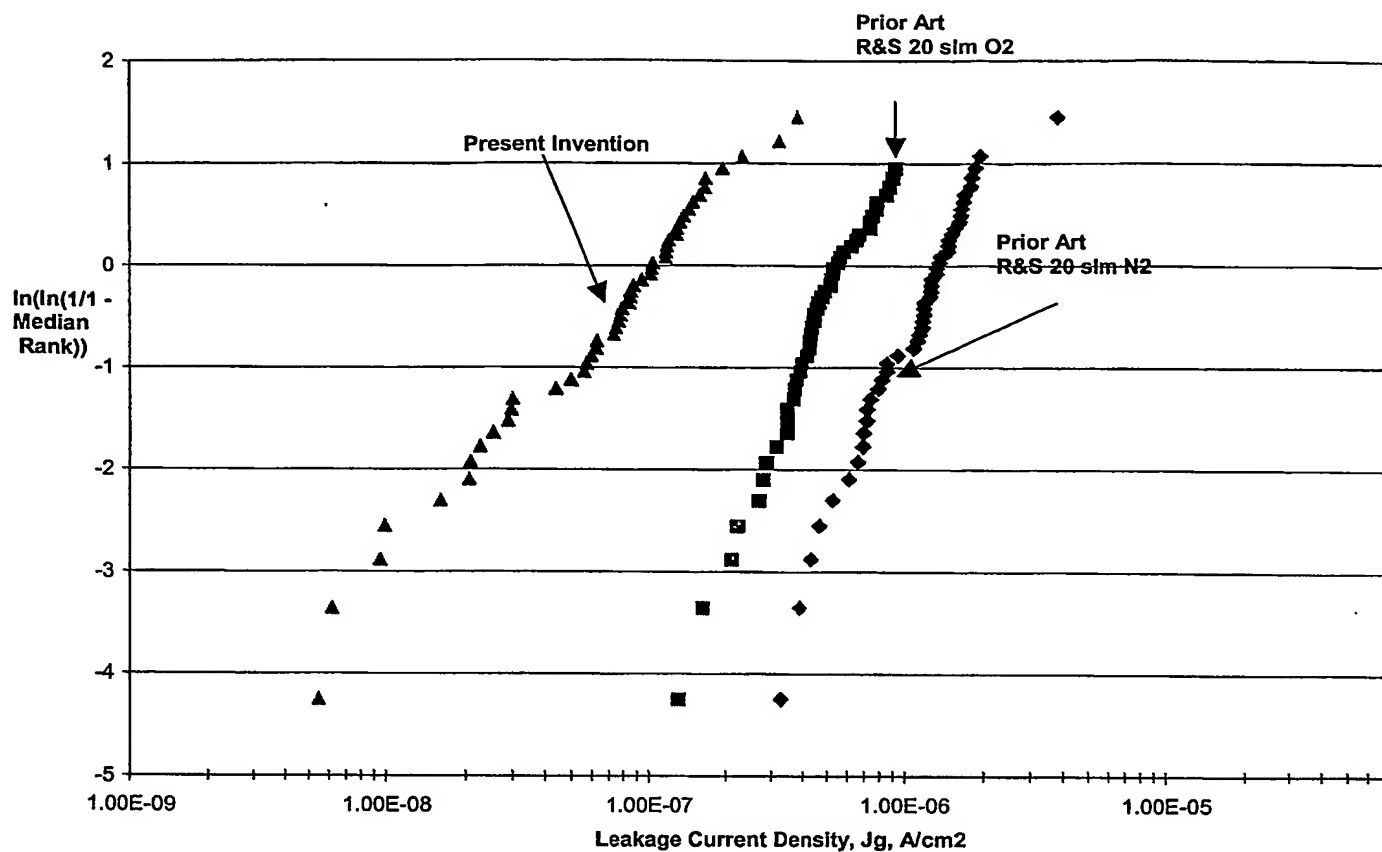
Present Invention



**FIG. 2**  
Leakage Current Density vs  $V_{gs}$  Charts for 900°C Wet Oxidation Using Various Oxygen Flows During Ramp & Stabilization Step as practiced in the prior art.



**FIG. 3**  
Leakage current density (J<sub>g</sub>) vs V<sub>gs</sub> for wet oxidation processes at different process temperatures.



**FIG. 4**  
Weibull plots for wet oxidation processes with and without ramp and stabilization step at 900°C